Génération de tests basés sur les modèles pour des systèmes sur puce avec cohérence de caches

Massimo Zendri & Abderahman Kriouile

STMicroelectronics DCG / IP dev / FVS

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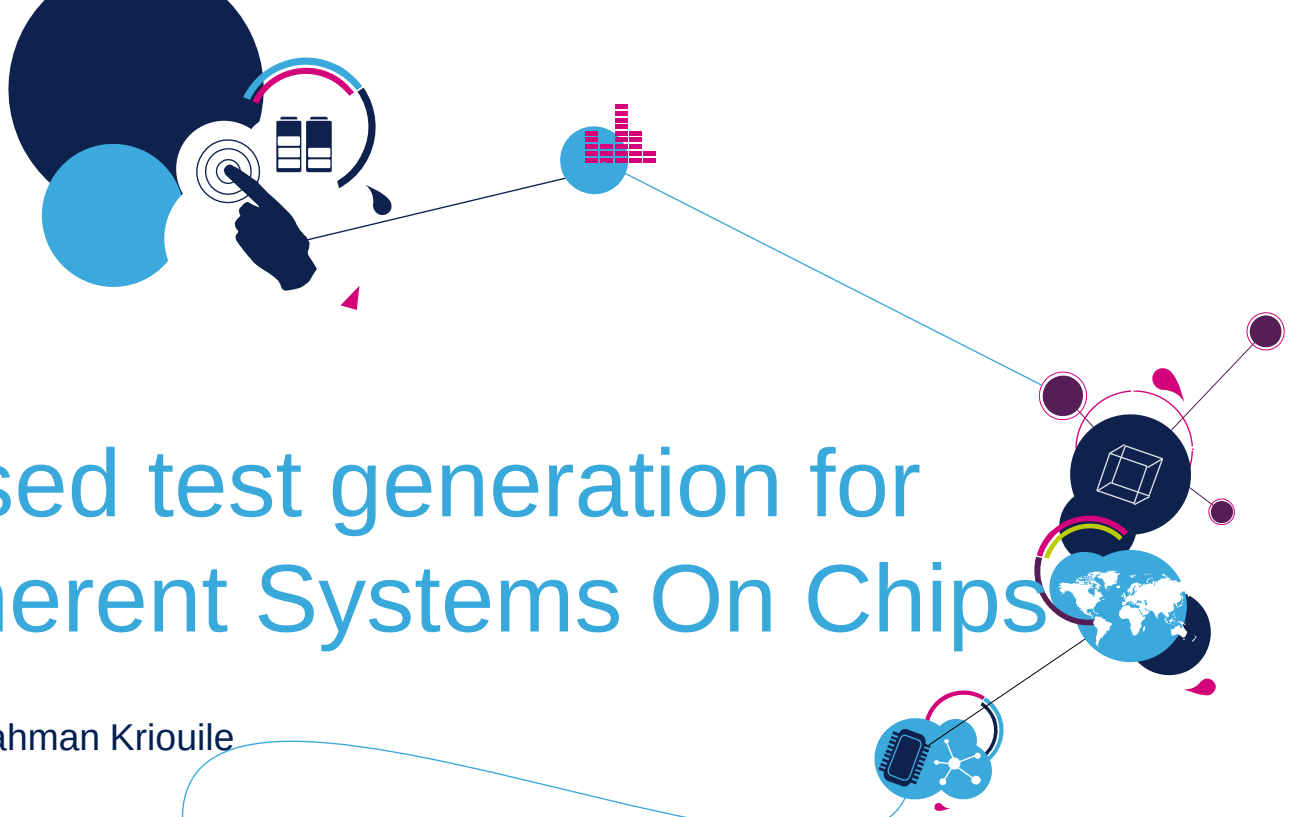

Model based test generation for cache coherent Systems On Chips

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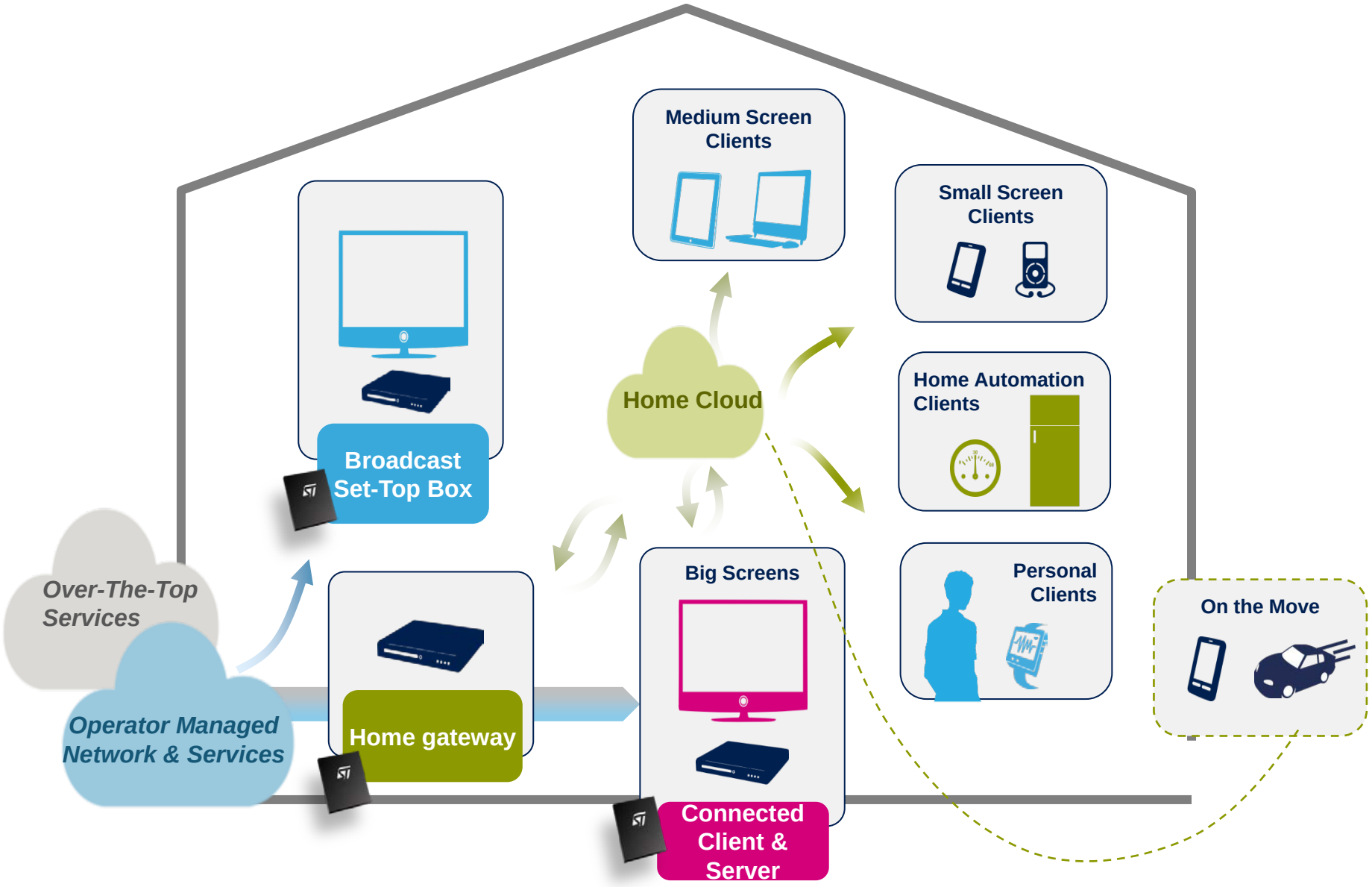
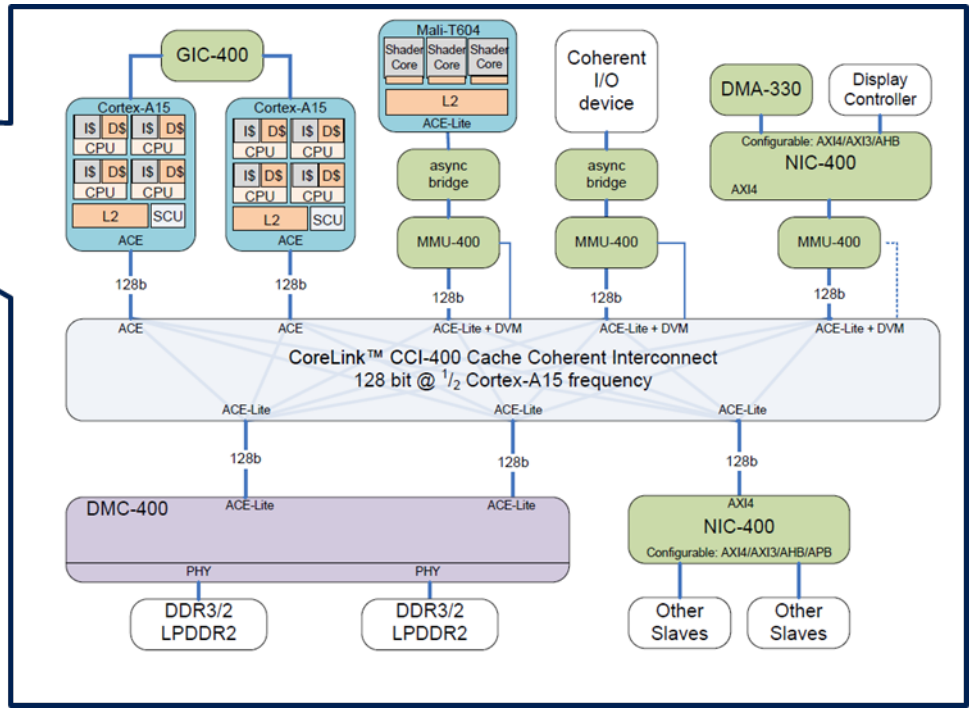
Towards the Home Cloud



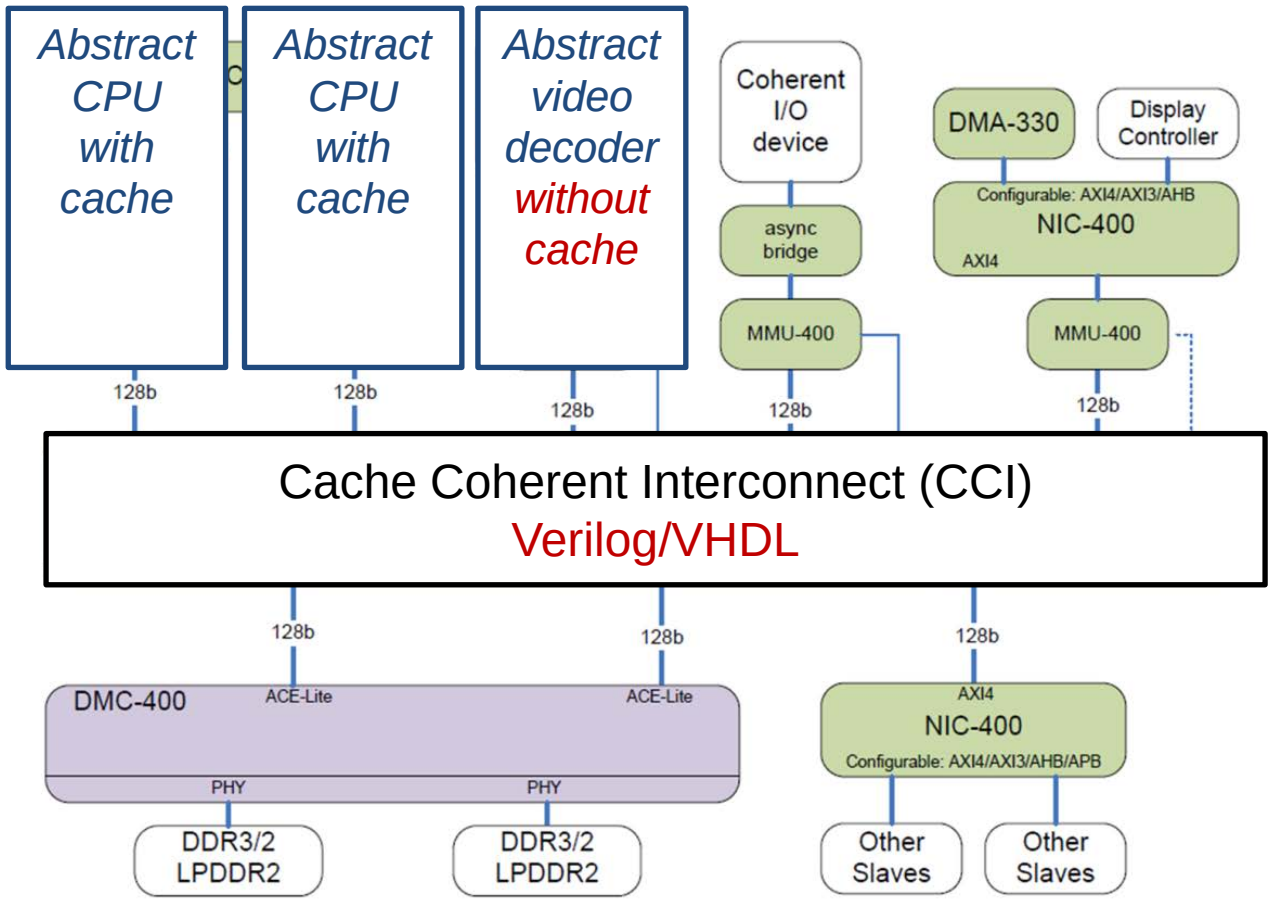
Heterogeneous System-on-Chip (SoC)



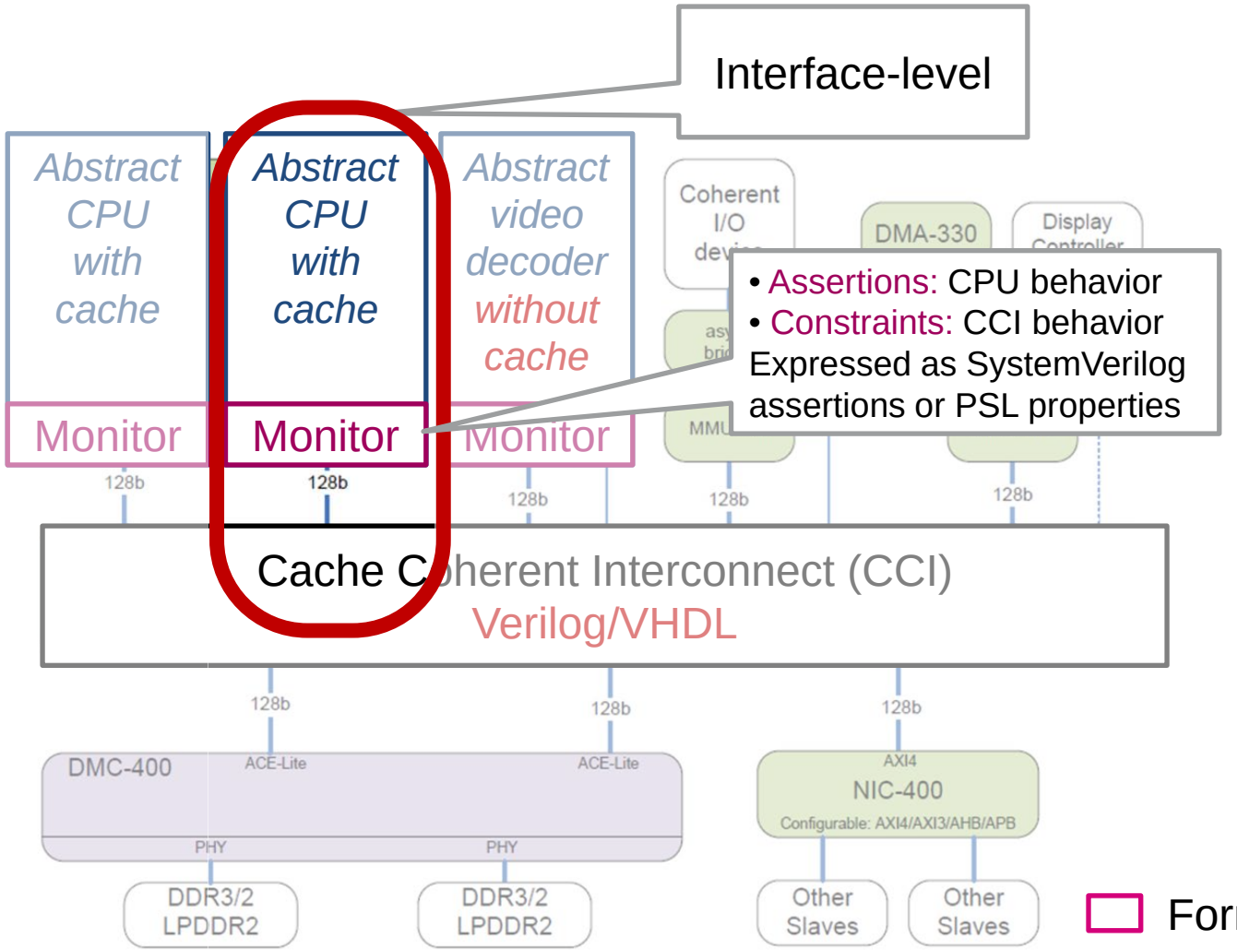
Need for System-Level Cache Coherency
ARM proposed ACE specification:
standard for system level cache coherency

State of the Art

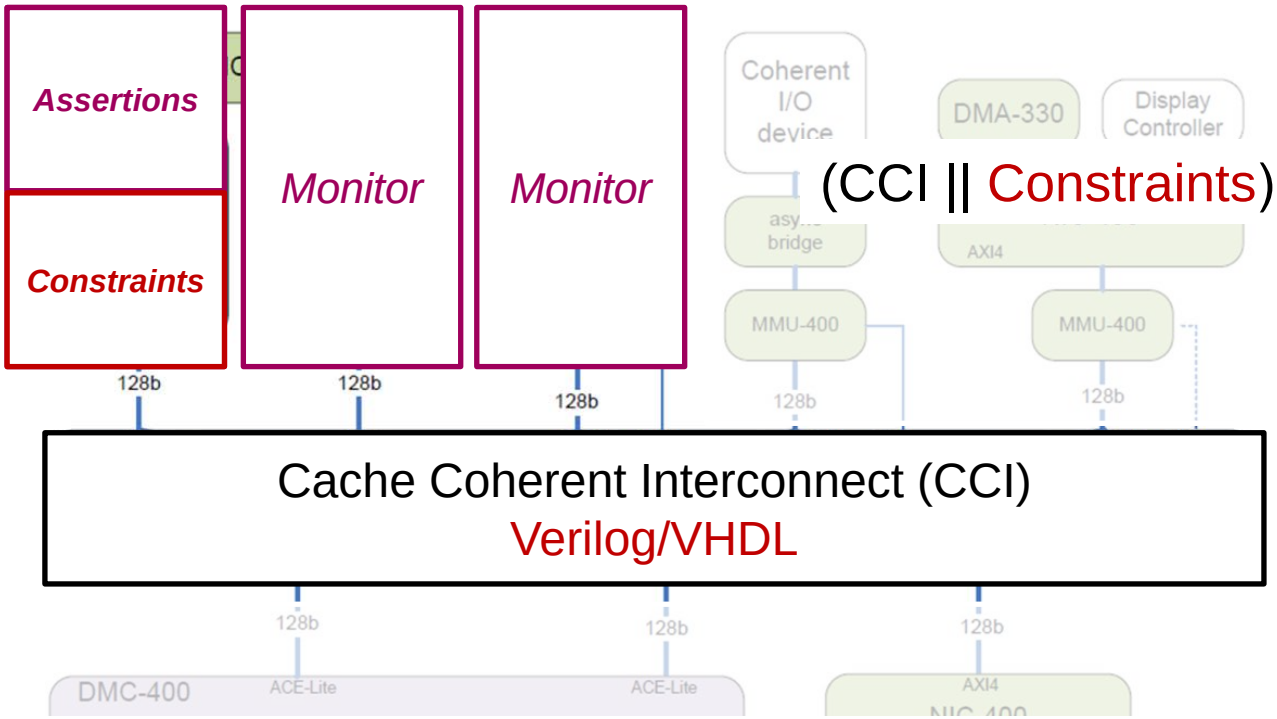
Simulation-Based Testing



Simulation-Based Testing



Model Checking
(without running any test)



$(CCI \parallel Constraints) \models Assertion_i$

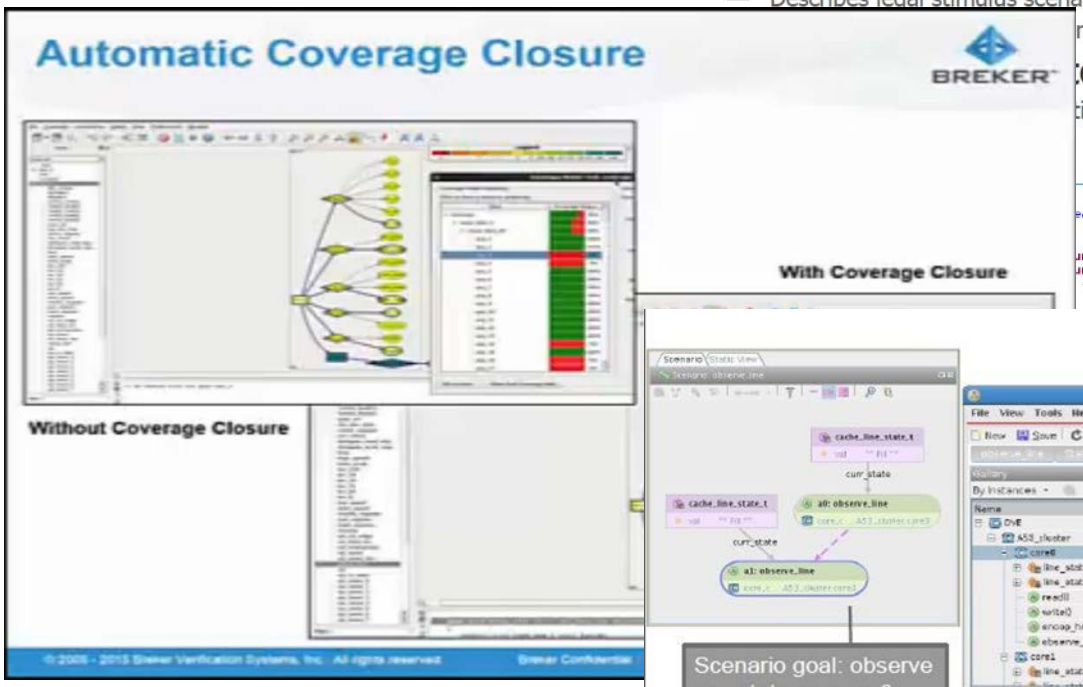
- Applying restrictions for more exploration
- Limitation due to state-space explosion problem

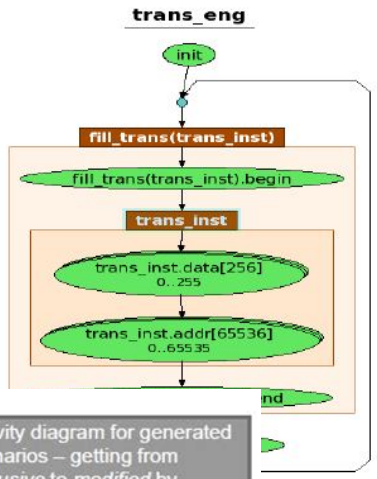
State of the Art

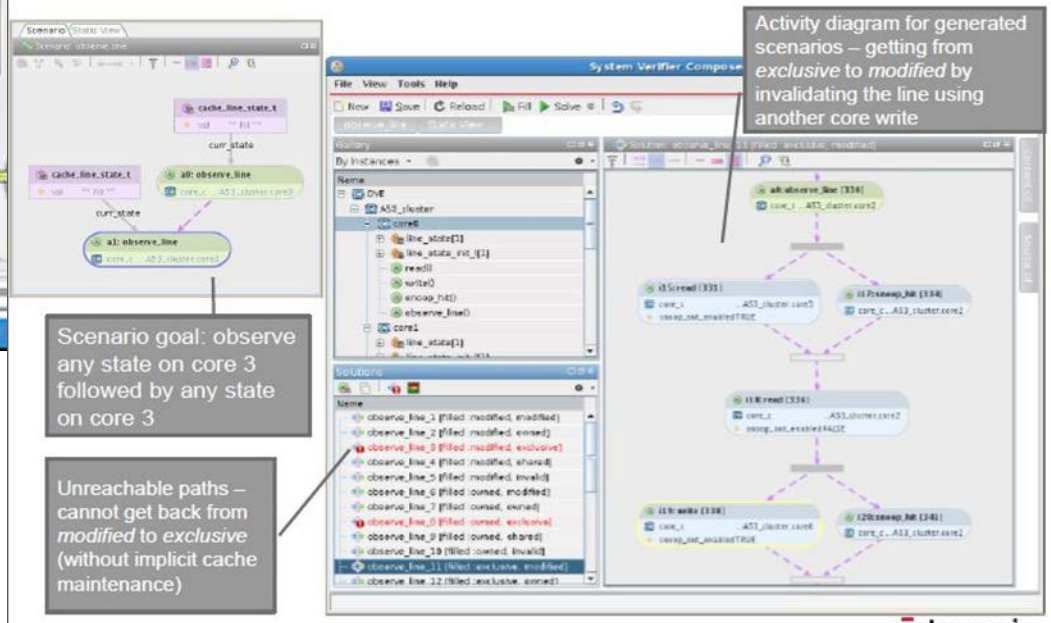
HW Model Based Test Generator

Graph-Based Stimulus Description

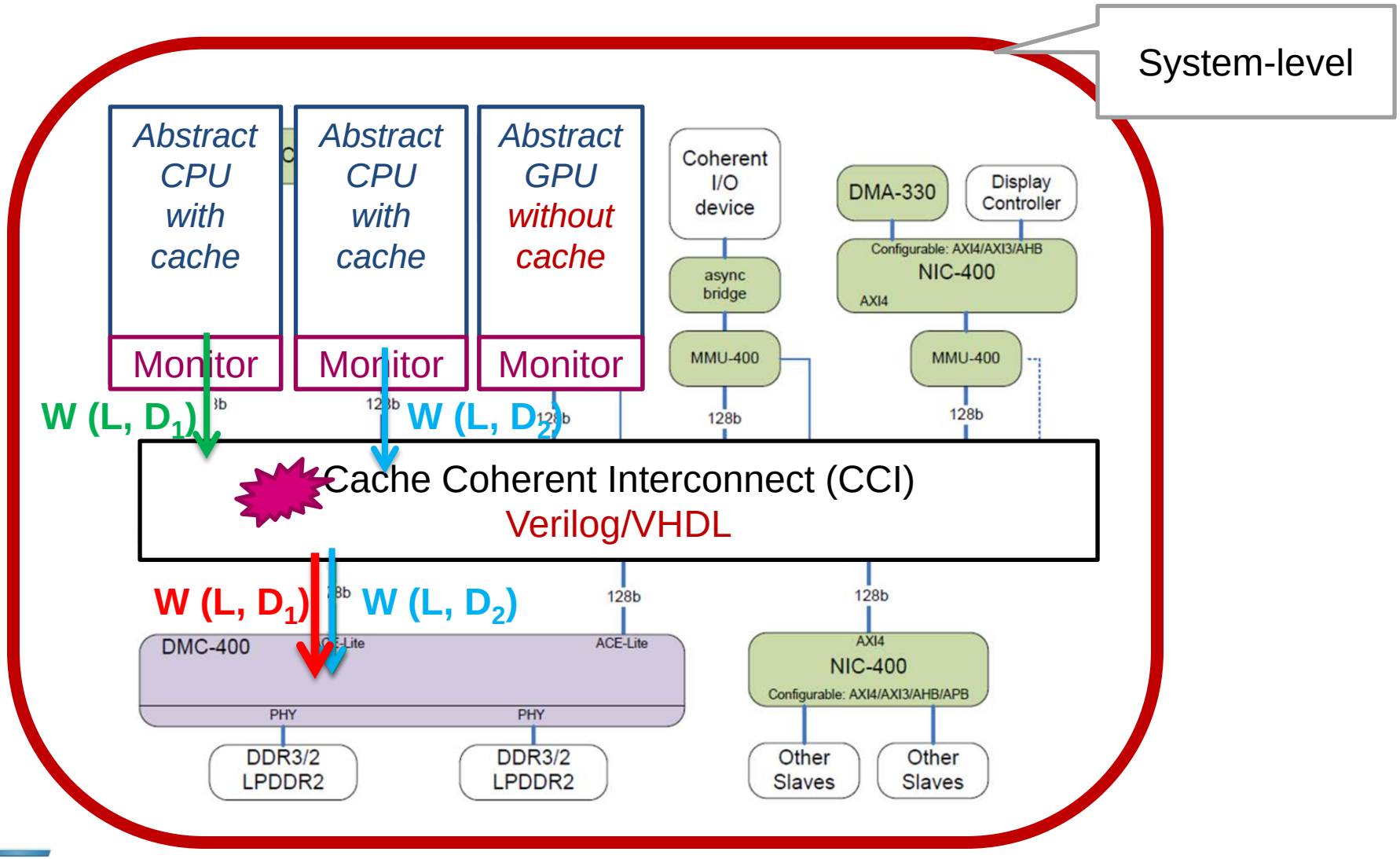
- Stimulus scenario described using Rules
  - Captures data and control flow aspects of test scenario
  - Describes legal stimulus scenario space



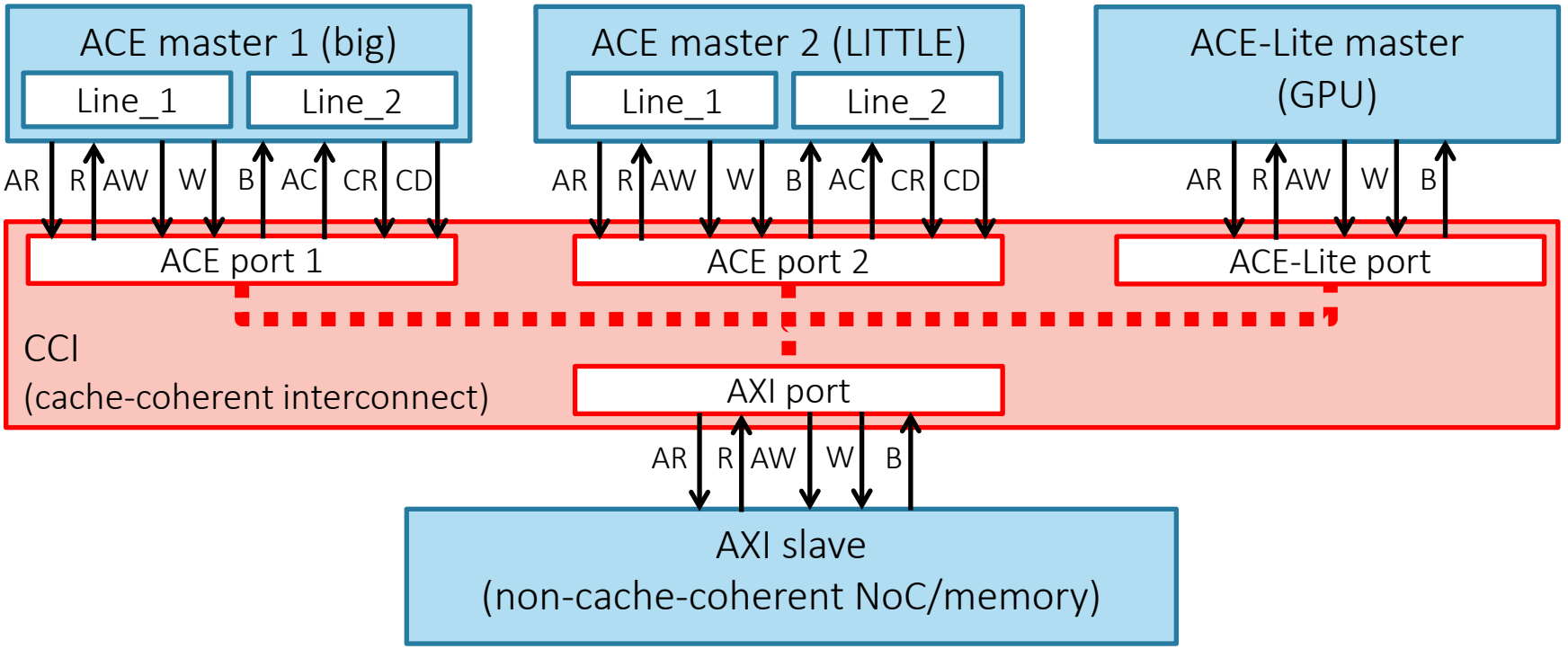




Need for System-Level Verification



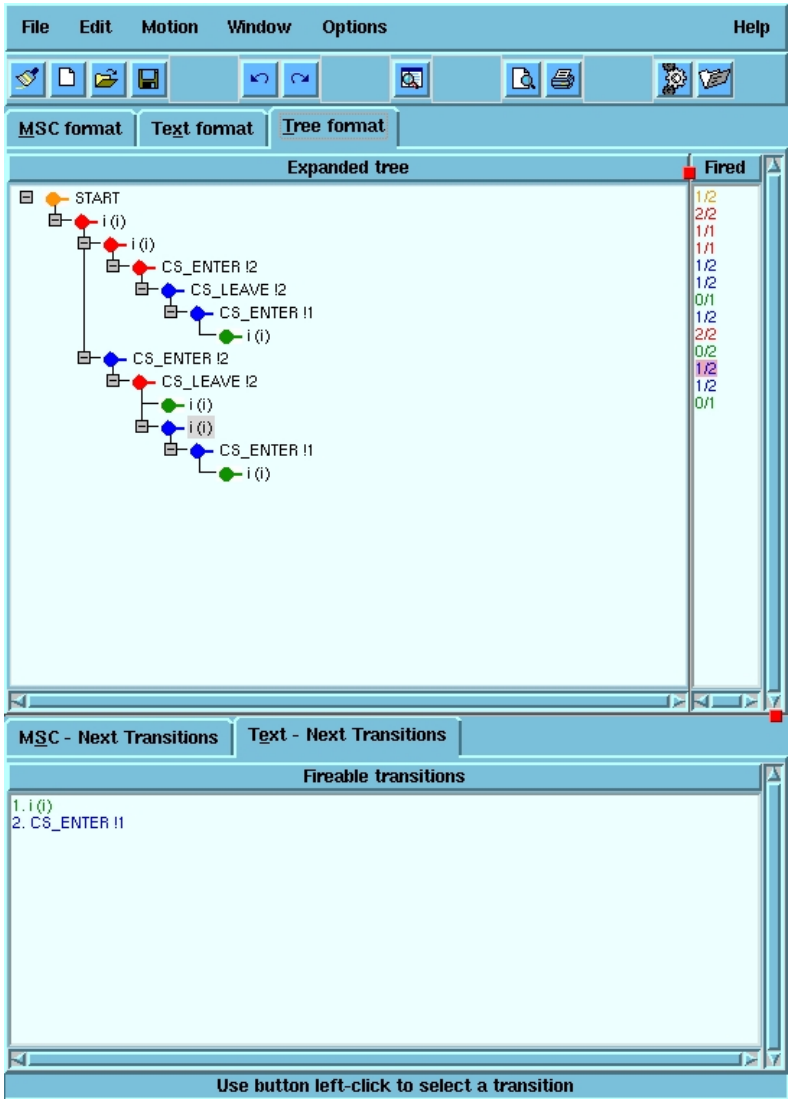
Formal Model of an ACE-based SoC



- Interface transfers modeled by rendezvous
- 3400 lines of LNT code derived from ACE specification
- Parametric: #masters, forbidden ACE transactions, …
- [Kriouile-Serwe-13] Formal Analysis of the ACE Specification for Cache Coherent Systems-on-Chip, FMICS, LNCS 8187, 2013

CADP: OCIS (*Open/Cæsar Interactive Simulator*)

- language-independent
- tree-like scenarios
- save/load scenarios
- source code access
- dynamic recompile



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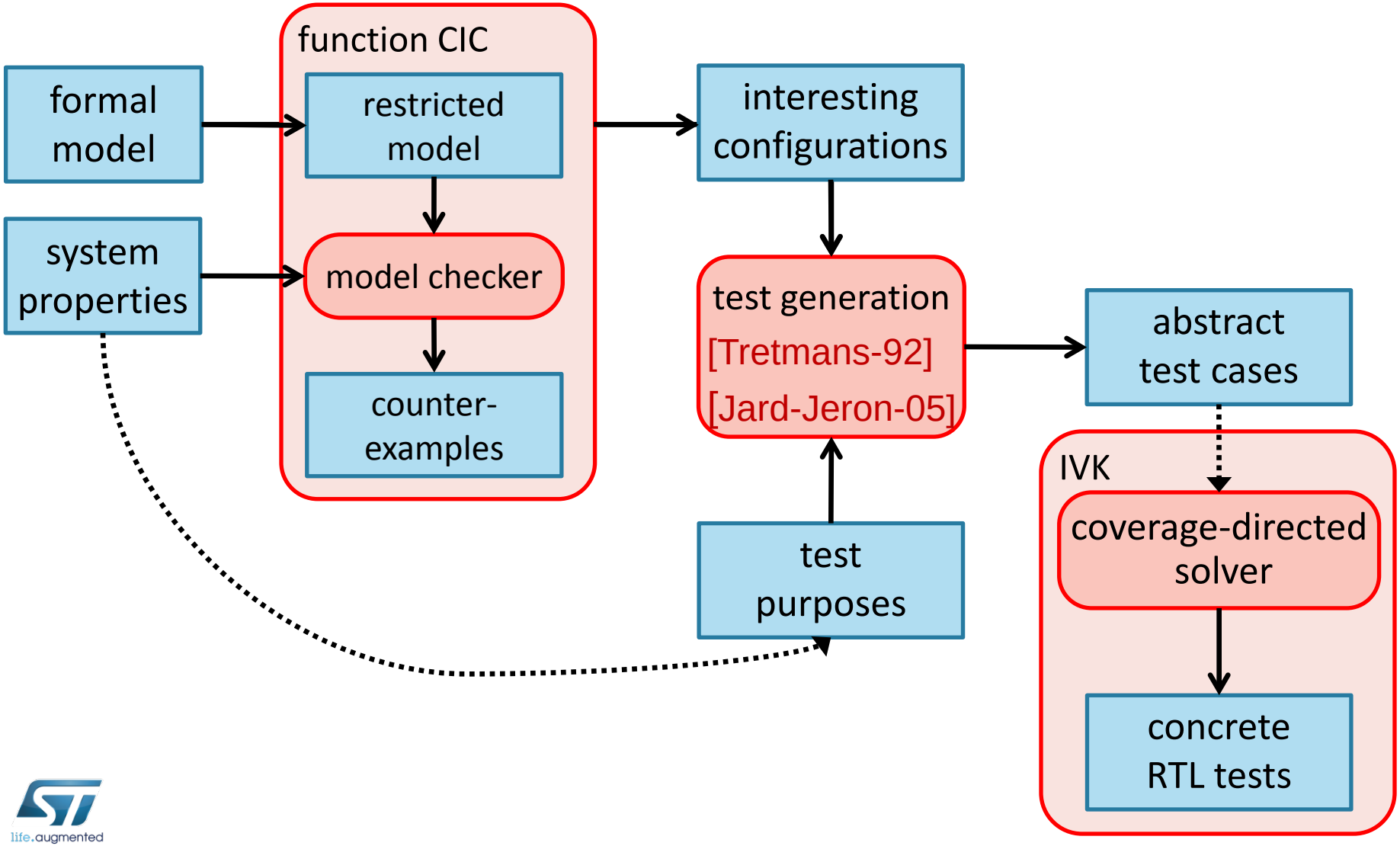
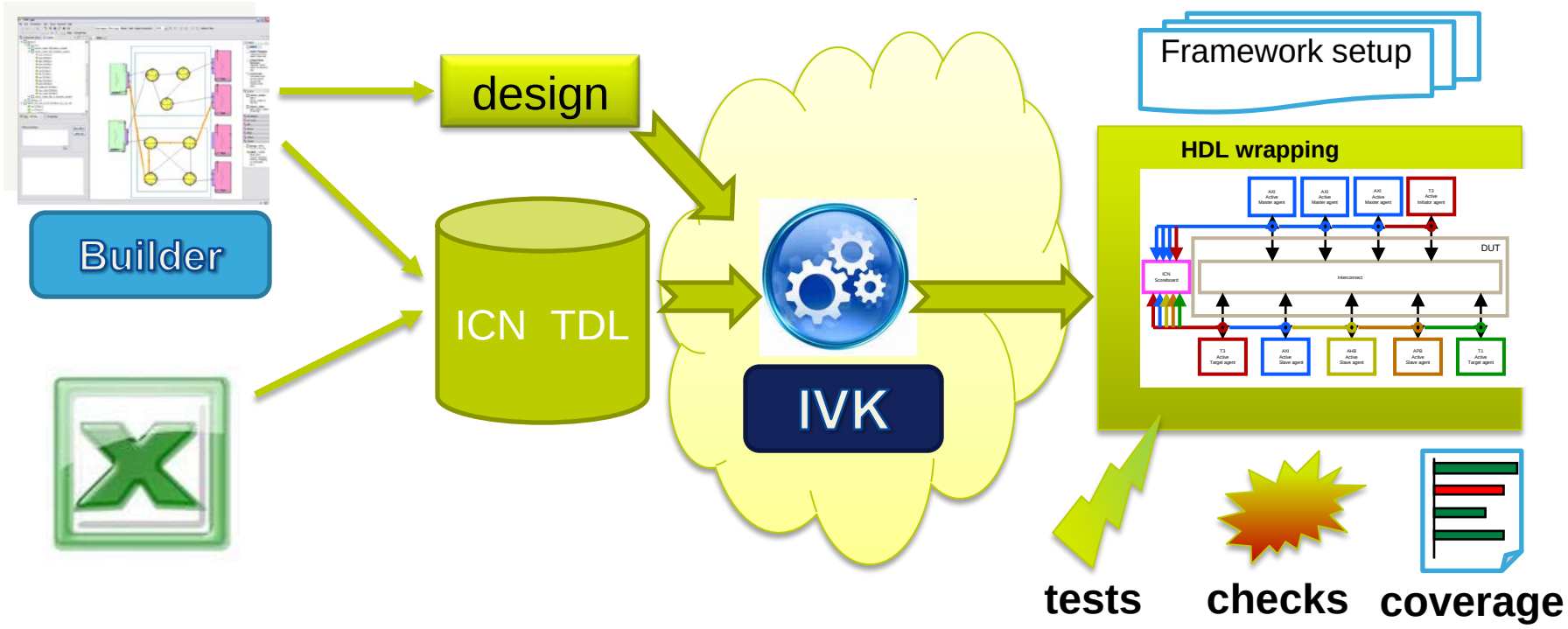
Generation of System-Level Test Cases



IVK (Interconnect Verification Kit):
Automated Interconnect Testbench Generation



- **Inputs**

  Architectural description (TDL) either generated by interconnect designers GUI or through Excel flow

- **Outputs**

  Full Verification Environment, including sequences and coverage models

Several Kinds of Derived Tests

- 39 + 3 generated CTGs (Complete Test Graphs)

prop.	masters	global CTG		extr.	nb. of	largest CTG		smallest CTG		extr.
		states	trans.	time	CTGs	states	trans.	states	trans.	time
φ_3	2ACE	6,402	14,323	>½ y	18	903	1,957	274	543	≃7h
φ_5	2ACE	23,032	48,543	>½ y	14	462	888	59	107	<1h
	1ACE/1Lite	2,815	7,071	>½ y	7	193	394	59	107	<1h

- 296 simple system-level tests
  - for each correct initial state with two masters possibly sharing a memory line, initiate all permitted transitions
  - check correct behavior of the Cache Coherent Interconnect (e.g., generation of corresponding snoops)
- 10 sequence tests to recreate counter-examples
  - concurrency between transactions
  - conditioned by response of the Cache Coherent Interconnect

Results

- 300 IVK tests generated
- Many problems identified on the verification environment (VIP components)
- System level assertions to check system behavior
- 100% coverage of system level assertions
- Reproduction of 1 suspected architectural issue
- Used on 2 currently developed products (codenamed Orly3 and Barcelona)